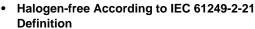


AO4900A-VB Datasheet

Dual N-Channel Enhancement Mode Field Effect Transistor with Schottky Diode

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A)	Q _g (Typ.)		
30	0.008 at V _{GS} = 10 V	8	15 nC		
30	0.012 at V _{GS} = 4.5 V	6.8	15110		

FEATURES





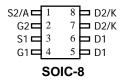
RoHS COMPLIANT HALOGEN

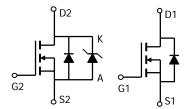
FREE

- Trench Power MOSFET
- 100 % UIS Tested
- 100 % R_q Tested
- Compliant to RoHS Directive 2002/95/EC

APPLICATIONS

- Set Top Box
- Low Current DC/DC





Absolute Maximum Ratings T_A=25°C unless otherwise noted **Parameter MOSFET** Schottky Units Symbol V_{DS} Drain-Source Voltage 30 V V_{GS} ٧ Gate-Source Voltage ±12 T_A=25°C 8 I_D Continuous Drain Current^A T_△=70°C 6.8 Α Pulsed Drain Current^B I_{DM} 40 V_{KA} Schottky reverse voltage ٧ 30 T_A=25°C 3 I_{F} T_^=70°C Continuous Forward Current^A 2 Α Pulsed Forward Current^B I_{FM} 40 T_A=25°C 2 2 P_D W T_Δ=70°C 1.44 1.44 **Power Dissipation** T_J , T_{STG} °C Junction and Storage Temperature Range -55 to 150 -55 to 150

Parameter: Thermal Characteris	Symbol	Тур	Max	Units	
Maximum Junction-to-Ambient ^A	t ≤ 10s	$R_{\theta JA}$	48	62.5	
Maximum Junction-to-Ambient ^A	Steady-State	Т	74	110	°C/W
Maximum Junction-to-Lead ^C	Steady-State	Steady-State R _{0JL}		40	
Thermal Characteristics Schottky					
Maximum Junction-to-Ambient ^A	t ≤ 10s	$R_{ hetaJA}$	47.5	62.5	
Maximum Junction-to-Ambient ^A	Steady-State	ТθЈА	71	110	°C/W
Maximum Junction-to-Lead ^C	Steady-State	$R_{ heta JL}$	32	40	



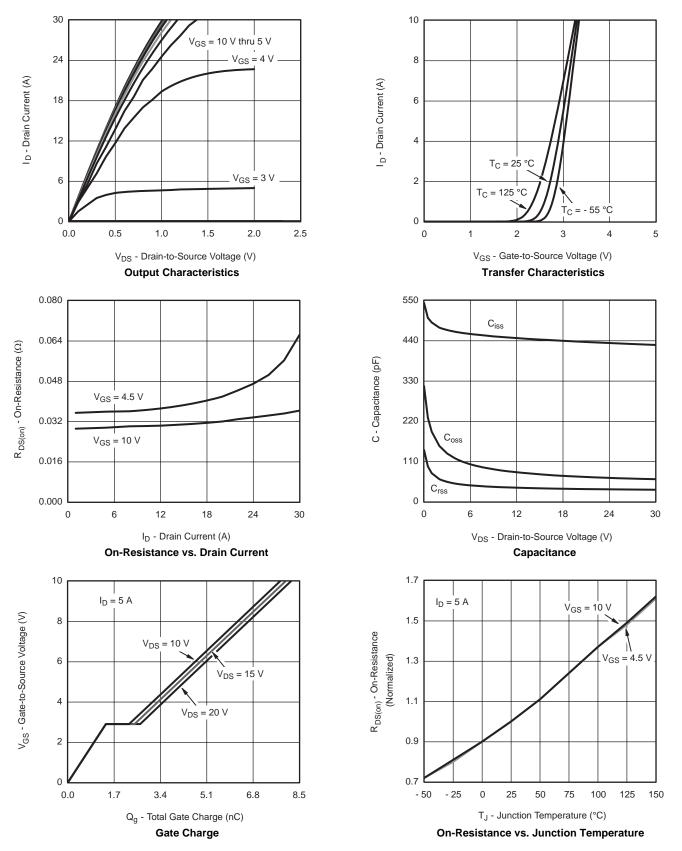
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static					L		
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 250 A		32		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	$I_{D} = 250 \mu A$		- 5.0			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_{D} = 250 \mu A$	1.0		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 30 V, V _{GS} = 0 V, T _J = 55 °C			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	10			Α	
	_ ` ′	V _{GS} = 10 V, I _D = 5 A		0.008			
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V, } I_D = 4 \text{ A}$		0.012		Ω	
Forward Transconductance ^a	g _{fs}	V _{DS} = 10 V, I _D = 5 A		16		S	
Dynamic ^b							
Input Capacitance	C _{iss}			586		pF	
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		117			
Reverse Transfer Capacitance	C _{rss}			55			
		$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 5 \text{ A}$		15		nC	
Total Gate Charge	Q _g			3.7	5.6		
Gate-Source Charge	Q_{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 5 \text{ A}$		1.4			
Gate-Drain Charge	Q_{gd}			1.05			
Gate Resistance	R _g	f = 1 MHz	0.8	4.3	8.6	Ω	
Turn-On Delay Time	t _{d(on)}			12	24		
Rise Time	t _r	V_{DD} = 15 V, R_L = 3 Ω		55	100		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 5$ A, V_{GEN} = 4.5 V, R_g = 1 Ω		11	22		
Fall Time	t _f			8	16	1	
Turn-On Delay Time	t _{d(on)}			4	8	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 3 Ω		9	18	- -	
Turn-Off Delay Time	t _{d(off)}	$I_D\cong$ 5 A, V_{GEN} = 10 V, R_g = 1 Ω		10	20		
Fall Time	t _f			6	12		
Drain-Source Body Diode Characteristi	cs				l	<u> </u>	
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			2.25		
Pulse Diode Forward Current	I _{SM}				24	A	
Body Diode Voltage	V _{SD}	I _S = 2 A, V _{GS} = 0 V		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			11	20	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	L 5 A 41/44 400 A/22 T 05 00		4	8	nC	
Reverse Recovery Fall Time	t _a	$I_F = 5 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$		7			
Reverse Recovery Rise Time	t _b	\dashv		4		ns	

Notes:

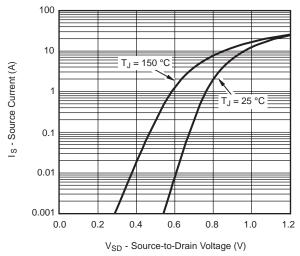
- a. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

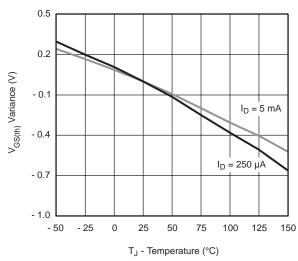




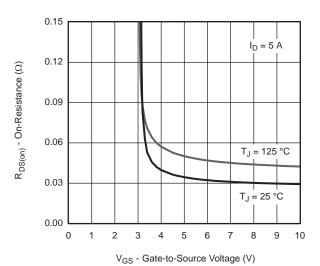




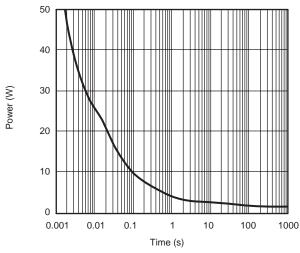
Source-Drain Diode Forward Voltage



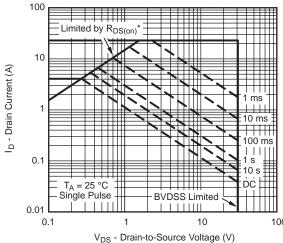
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage



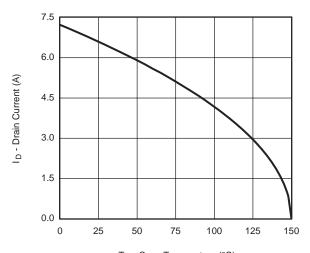
Single Pulse Power



* V_{GS} > minimum V_{GS} at which R_{DS(on)} is specified

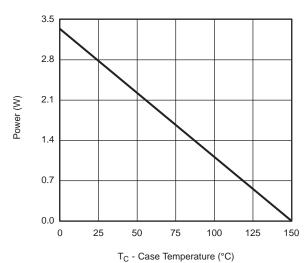
Safe Operating Area, Junction-to-Ambient

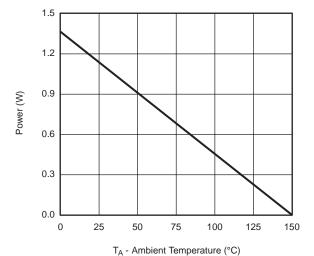




 $T_{\mbox{\scriptsize C}}$ - Case Temperature (°C)

Current Derating*



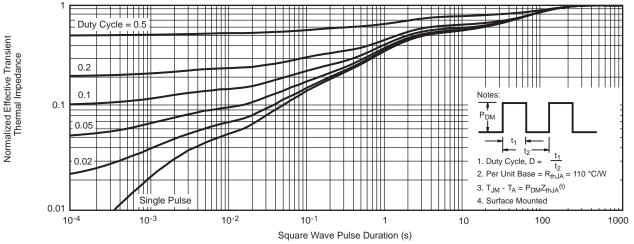


Power, Junction-to-Foot

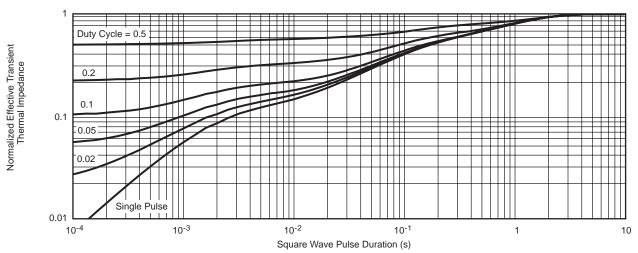
Power, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





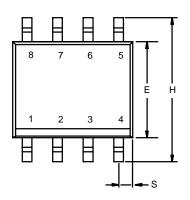
Normalized Thermal Transient Impedance, Junction-to-Ambient

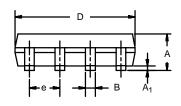


Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012





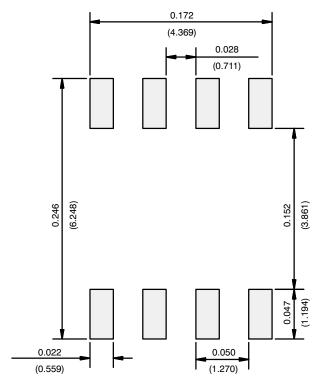


	MILLIMETERS		INC	HES	
DIM	Min	Max	Min	Max	
Α	1.35	1.75	0.053	0.069	
A ₁	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
FCN: C-06527-Rev. L 11-Sen-06					

ECN: C-06527-Rev. I, 11-Sep-06 DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)

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